# MOSFET – Power, Dual, N-Channel, POWERTRENCH®, Power Clip, Asymmetric

## 25 V

# NTMFD1D4N02P1E

| FET | $V_{(BR)DSS}$ | $R_{DS(on)}$ MAX | $I_D$ MAX |
|---|---|---|---|
| Q1 | 25 V | 3.3 mΩ @ 10 V | 74 A |
| | | 4.2 mΩ @ 4.5 V | |
| Q2 | 25 V | 1.1 mΩ @ 10 V | 155 A |
| | | 1.33 mΩ @ 4.5 V | |

### Features

- Small Footprint (5x6mm) for Compact Design
- Low $R_{DS(on)}$ to Minimize Conduction Losses
- Low $Q_G$ and Capacitance to Minimize Driver Losses
- These are Pb-free, Halogen Free / BFR Free and are RoHS Compliant

### Typical Applications

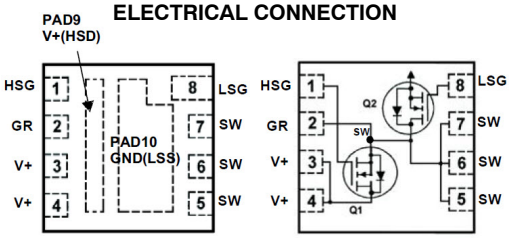
- DC-DC Converters
- System Voltage Rails


**PQFN8**
**POWER CLIP**
**CASE 483AR**

### MARKING DIAGRAM


2EKN = Specific Device Code
A = Assembly Location
Y = Year
WW = Work Week
ZZ = Assembly Lot Code

### ELECTRICAL CONNECTION




### MAXIMUM RATINGS ($T_J$ = 25 °C unless otherwise stated)

| Parameter | | | Symbol | Q1 | Q2 | Unit |
|---|---|---|---|---|---|---|
| Drain-to-Source Voltage | | | $V_{DSS}$ | 25 | 25 | V |
| Gate-to-Source Voltage | | | $V_{GS}$ | +16V −12V | +16V −12V | V |
| Continuous Drain Current $R_{\theta JC}$ (Note 3) | Steady State | $T_C$ = 25 °C | $I_D$ | 74 | 155 | A |
| | | $T_C$ = 85 °C | | 53 | 112 | |
| Power Dissipation $R_{\theta JC}$ (Note 3) | | $T_A$ = 25 °C | $P_D$ | 25 | 41 | W |
| Continuous Drain Current $R_{\theta JA}$ (Notes 1, 3) | Steady State | $T_A$ = 25 °C | $I_D$ | 20 | 36 | A |
| | | $T_A$ = 85 °C | | 14 | 26 | |
| Power Dissipation $R_{\theta JA}$ (Notes 1, 3) | | $T_A$ = 25 °C | $P_D$ | 2.1 | 2.3 | W |
| Continuous Drain Current $R_{\theta JA}$ (Notes 2, 3) | Steady State | $T_A$ = 25 °C | $I_D$ | 13 | 24 | A |
| | | $T_A$ = 85 °C | | 10 | 17 | |
| Power Dissipation $R_{\theta JA}$ (Notes 2, 3) | | $T_A$ = 25 °C | $P_D$ | 0.96 | 1.0 | W |
| Pulsed Drain Current | $T_A$ = 25 °C, $t_p$ = 10 μs | | $I_{DM}$ | 325 | 552 | A |
| Single Pulse Drain-to-Source Avalanche Energy Q1: $I_L$ = 9.4 $A_{pk}$, L = 3 mH (Note 4) Q2: $I_L$ = 20.1 $A_{pk}$, L = 3 mH (Note 4) | | | $E_{AS}$ | 134 | 604 | mJ |
| Operating Junction and Storage Temperature Range | | | $T_J$, $T_{stg}$ | −55 to 150 | | °C |
| Lead Temperature Soldering Reflow for Soldering Purposes (1/8″ from case for 10 s) | | | $T_L$ | 260 | | °C |

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

### ORDERING INFORMATION

| Device | Package | Shipping† |
|---|---|---|
| NTMFD1D4N02P1E | PQFN8 (Pb-Free) | 3000 / Tape & Reel |

† For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

**Table 1. THERMAL RESISTANCE RATINGS**

| Parameter | Symbol | Q1 Max | Q2 Max | Units |
|---|---|---|---|---|
| Junction-to-Case – Steady State (Note 1, 3) | $R_{\theta JC}$ | 4.4 | 2.9 | °C/W |
| Junction-to-Ambient – Steady State (Note 1, 3) | $R_{\theta JA}$ | 60 | 55 | |
| Junction-to-Ambient – Steady State (Note 2, 3) | $R_{\theta JA}$ | 130 | 120 | |

1. Surface-mounted on FR4 board using 1 $in^2$ pad size, 2 oz Cu pad.
2. Surface-mounted on FR4 board using minimum pad size, 2 oz Cu pad.
3. The entire application environment impacts the thermal resistance values shown. They are not constants and are only valid for the particular conditions noted. Actual continuous current will be limited by thermal & electro-mechanical application board design. $R_{\theta CA}$ is determined by the user's board design.
4. Q1 100% UIS tested at L = 0.1 mH, $I_{AS}$ = 16.5 A.
   Q2 100% UIS tested at L = 0.1 mH, $I_{AS}$ = 36 A.

**Table 2. ELECTRICAL CHARACTERISTICS** ($T_J$ = 25 °C unless otherwise stated)

| Parameter | Symbol | Test Condition | | FET | Min | Typ | Max | Unit |
|---|---|---|---|---|---|---|---|---|
| **OFF CHARACTERISTICS** | | | | | | | | |
| Drain-to-Source Breakdown Voltage | $V_{(BR)DSS}$ | $V_{GS}$ = 0 V, $I_D$ = 250 μA | | Q1 | 25 | | | V |
| Drain-to-Source Breakdown Voltage | $V_{(BR)DSS}$ | $V_{GS}$ = 0 V, $I_D$ = 1 mA | | Q2 | 25 | | | V |
| Drain-to-Source Breakdown Voltage Temperature Coefficient | $V_{(BR)DSS}$ / $T_J$ | $I_D$ = 250 μA, ref to 25 °C | | Q1 | | 16 | | mV/°C |
| | | $I_D$ = 1 mA, ref to 25 °C | | Q2 | | 19 | | |
| Zero Gate Voltage Drain Current | $I_{DSS}$ | $V_{GS}$ = 0 V, $V_{DS}$ = 20 V | $T_J$ = 25 °C | Q1 | | | 10 | μA |
| | | | | Q2 | | | 10 | |
| Gate-to-Source Leakage Current | $I_{GSS}$ | $V_{DS}$ = 0 V, $V_{GS}$ = +16 V / −12 V | | Q1 | | | ±100 | nA |
| | | $V_{DS}$ = 0 V, $V_{GS}$ = +16 V / −12 V | | Q2 | | | ±100 | |
| **ON CHARACTERISTICS** (Note 5) | | | | | | | | |
| Gate Threshold Voltage | $V_{GS(TH)}$ | $V_{GS}$ = $V_{DS}$, $I_D$ = 250 μA | | Q1 | 1.2 | 1.54 | 2.0 | V |
| | | $V_{GS}$ = $V_{DS}$, $I_D$ = 800 μA | | Q2 | 1.2 | 1.55 | 2.0 | |
| Threshold Temperature Coefficient | $V_{GS(TH)}$ / $T_J$ | $I_D$ = 250 μA, ref to 25 °C | | Q1 | | −4.3 | | mV/°C |
| | | $I_D$ = 800 μA, ref to 25 °C | | Q2 | | −4.4 | | |
| Drain-to-Source On Resistance | $R_{DS(on)}$ | $V_{GS}$ = 10 V, $I_D$ = 20 A | | Q1 | | 2.6 | 3.3 | mΩ |
| | | $V_{GS}$ = 4.5 V, $I_D$ = 18 A | | | | 3.4 | 4.2 | |
| | | $V_{GS}$ = 10 V, $I_D$ = 37 A | | Q2 | | 0.81 | 1.1 | |
| | | $V_{GS}$ = 4.5 V, $I_D$ = 33 A | | | | 1.04 | 1.33 | |
| Forward Transconductance | $g_{FS}$ | $V_{DS}$ = 5 V, $I_D$ = 20 A | | Q1 | | 125 | | |
| | | $V_{DS}$ = 5 V, $I_D$ = 37 A | | Q2 | | 285 | | |
| Gate Resistance | $R_G$ | $T_A$ = 25 °C | | Q1 | | 0.44 | | Ω |
| | | | | Q2 | | 0.6 | | |
| **CHARGES & CAPACITANCES** | | | | | | | | |
| Input Capacitance | $C_{ISS}$ | $V_{GS}$ = 0 V, $V_{DS}$ = 13 V, f = 1 MHz | | Q1 | | 1180 | | pF |
| | | | | Q2 | | 3603 | | |
| Output Capacitance | $C_{OSS}$ | | | Q1 | | 320 | | pF |
| | | | | Q2 | | 940 | | |
| Reverse Capacitance | $C_{RSS}$ | | | Q1 | | 22 | | pF |
| | | | | Q2 | | 64 | | |

5. Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%
6. Switching characteristics are independent of operating junction temperatures

**Table 2. ELECTRICAL CHARACTERISTICS** ($T_J$ = 25 °C unless otherwise stated) (continued)

| Parameter | Symbol | Test Condition | | FET | Min | Typ | Max | Unit |
|---|---|---|---|---|---|---|---|---|
| **CHARGES & CAPACITANCES** | | | | | | | | |
| Total Gate Charge | $Q_{G(TOT)}$ | Q1: $V_{GS}$ = 4.5V, $V_{DS}$ = 13V, $I_D$ = 20A<br>Q2: $V_{GS}$ = 4.5V, $V_{DS}$ = 13V, $I_D$ = 37A | | Q1 | | 7.2 | | nC |
| | | | | Q2 | | 21.5 | | |
| Gate-to-Drain Charge | $Q_{GD}$ | | | Q1 | | 1.35 | | nC |
| | | | | Q2 | | 3.9 | | |
| Gate-to-Source Charge | $Q_{GS}$ | | | Q1 | | 3.15 | | nC |
| | | | | Q2 | | 9.1 | | |
| Total Gate Charge | $Q_{G(TOT)}$ | $V_{GS}$ = 10 V, $V_{DS}$ = 13 V, $I_D$ = 20 A | | Q1 | | 16.4 | | nC |
| | | $V_{GS}$ = 10 V, $V_{DS}$ = 13 V, $I_D$ = 37 A | | Q2 | | 48.6 | | |
| **SWITCHING CHARACTERISTICS, VGS = 4.5 V** (Note 6) | | | | | | | | |
| Turn-On Delay Time | $t_{d(ON)}$ | $V_{GS}$ = 4.5 V<br>Q1: $I_D$ = 20 A, $V_{DD}$ = 13 V, $R_G$ = 6Ω<br>Q2: $I_D$ = 37 A, $V_{DD}$ = 13 V, $R_G$ = 6Ω | | Q1 | | 11.6 | | ns |
| | | | | Q2 | | 21.4 | | |
| Rise Time | $t_{r(ON)}$ | | | Q1 | | 2.7 | | ns |
| | | | | Q2 | | 8.7 | | |
| Turn-Off Delay Time | $t_{d(OFF)}$ | | | Q1 | | 15.6 | | ns |
| | | | | Q2 | | 30.7 | | |
| Fall Time | $t_f$ | | | Q1 | | 3.2 | | ns |
| | | | | Q2 | | 8.5 | | |
| **SWITCHING CHARACTERISTICS, VGS = 10 V** (Note 6) | | | | | | | | |
| Turn-On Delay Time | $t_{d(ON)}$ | $V_{GS}$ = 10 V<br>Q1: $I_D$ = 20 A, $V_{DD}$ = 13 V, $R_G$ = 6Ω<br>Q2: $I_D$ = 37 A, $V_{DD}$ = 13 V, $R_G$ = 6Ω | | Q1 | | 7.9 | | ns |
| | | | | Q2 | | 10.2 | | |
| Rise Time | $t_{r(ON)}$ | | | Q1 | | 1.1 | | ns |
| | | | | Q2 | | 3.3 | | |
| Turn-Off Delay Time | $t_{d(OFF)}$ | | | Q1 | | 21.3 | | ns |
| | | | | Q2 | | 48.9 | | |
| Fall Time | $t_f$ | | | Q1 | | 2.2 | | ns |
| | | | | Q2 | | 7.4 | | |
| **SOURCE-TO-DRAIN DIODE CHARACTERISTICS** | | | | | | | | |
| Forward Diode Voltage | $V_{SD}$ | $V_{GS}$ = 0 V, $I_S$ = 20 A | $T_J$ = 25 °C | Q1 | | 0.8 | 1.2 | V |
| | | | $T_J$ = 125 °C | | | 0.7 | | |
| | | $V_{GS}$ = 0 V, $I_S$ = 37 A | $T_J$ = 25 °C | Q2 | | 0.8 | 1.2 | |
| | | | $T_J$ = 125 °C | | | 0.65 | | |
| Reverse Recovery Time | $t_{RR}$ | $V_{GS}$ = 0 V,<br>Q1: $I_S$ = 20 A, dI/dt = 100 A/μs<br>Q2: $I_S$ = 37 A, dI/dt = 300 A/μs | | Q1 | | 21.4 | | ns |
| | | | | Q2 | | 36.5 | | |
| Reverse Recovery Charge | $Q_{RR}$ | | | Q1 | | 8.3 | | nC |
| | | | | Q2 | | 21.9 | | |

5. Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%
6. Switching characteristics are independent of operating junction temperatures

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

## TYPICAL CHARACTERISTICS FOR Q1

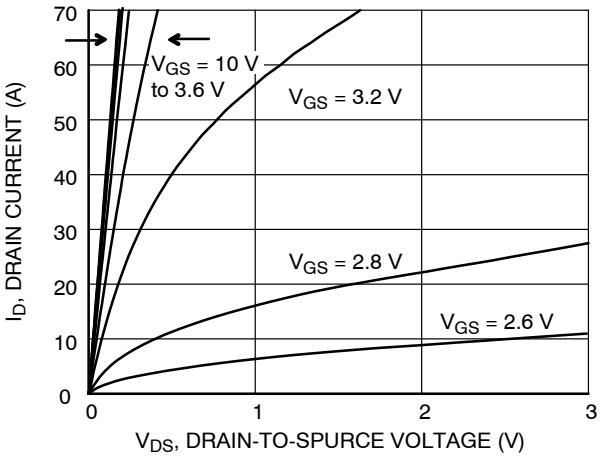



**Figure 1. On-Region Characteristics**

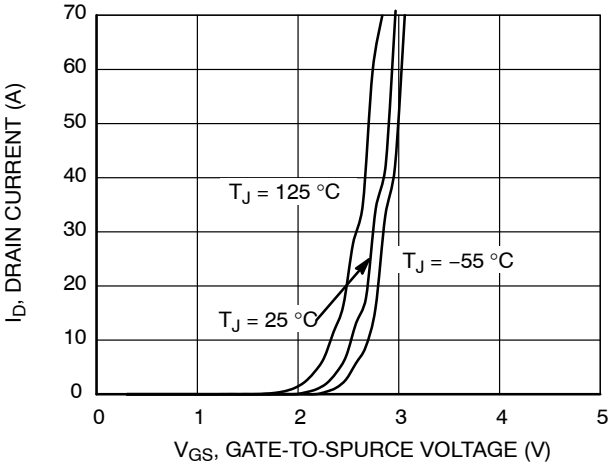



**Figure 2. Transfer Characteristics**

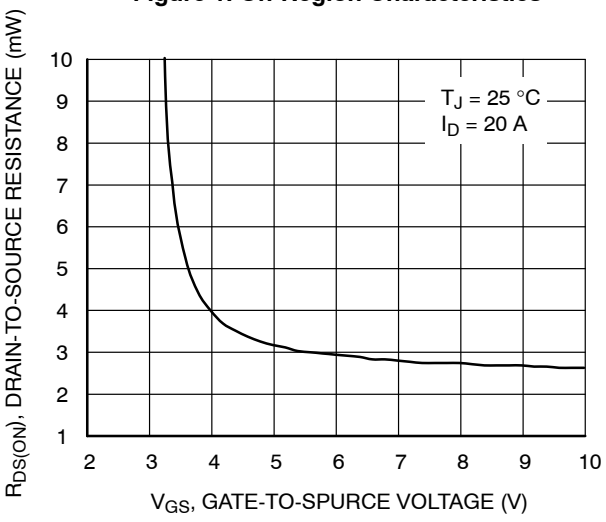



**Figure 3. On-Resistance vs. Gate-to-Source Voltage**

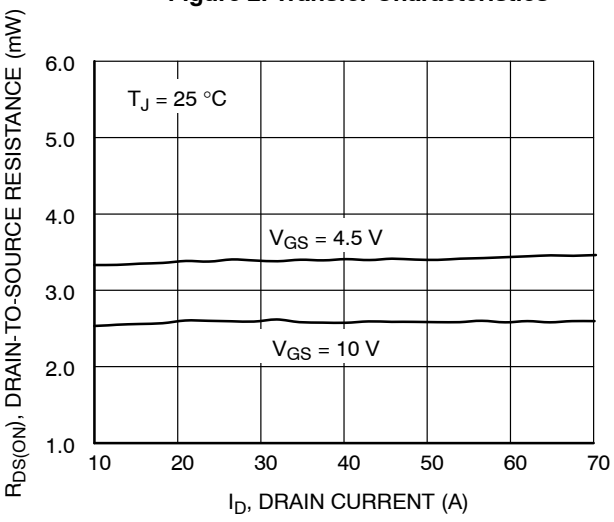



**Figure 4. On-Resistance vs. Drain Current and Gate Voltage**

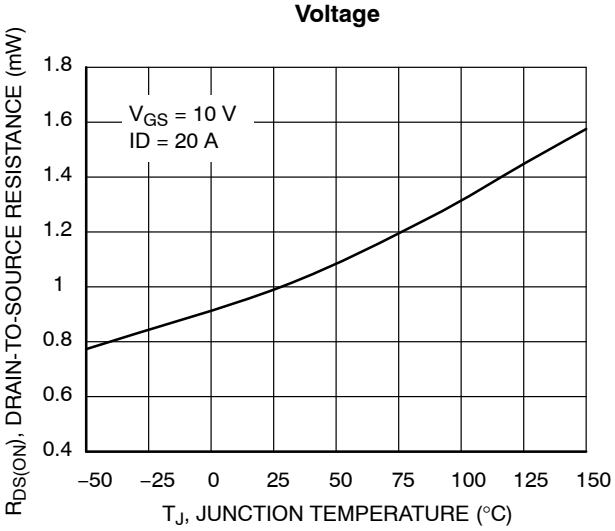



**Figure 5. On-Resistance Variation with Temperature**

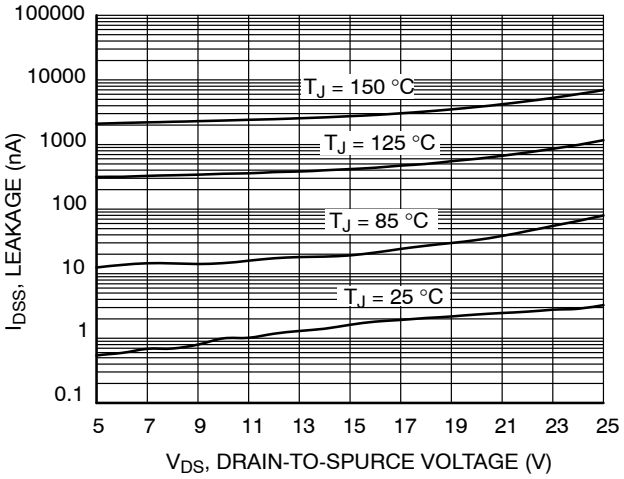



**Figure 6. Drain-to-Source Leakage Current vs. Voltage**

## TYPICAL CHARACTERISTICS FOR Q1 (continued)

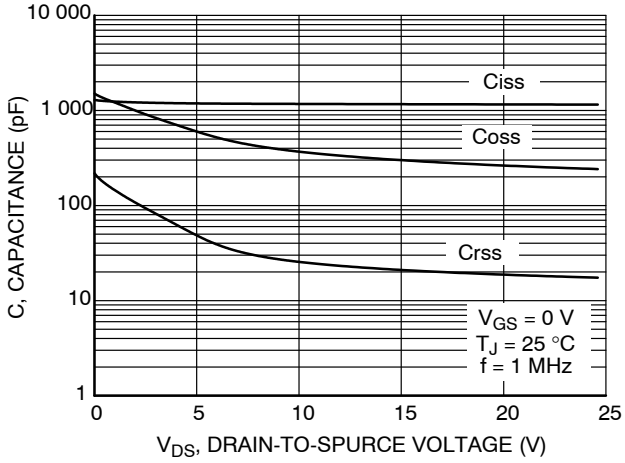



**Figure 7. Capacitance Variation**

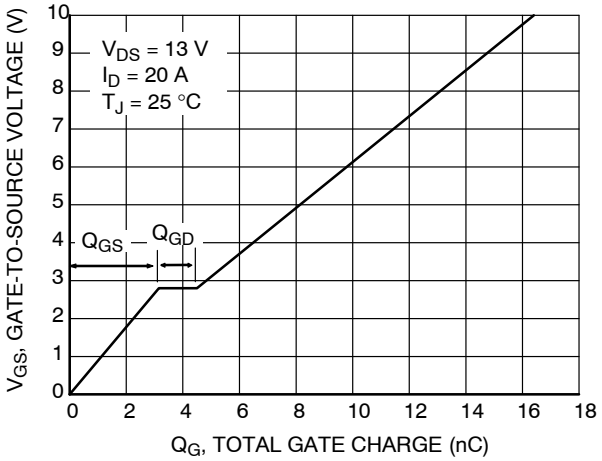



**Figure 8. Gate-to-Source vs. Total Charge**

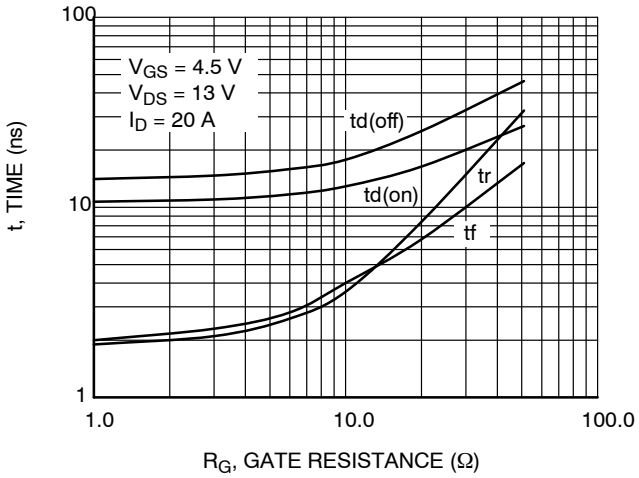



**Figure 9. Resistive Switching Time Variation vs. Gate Resistance**

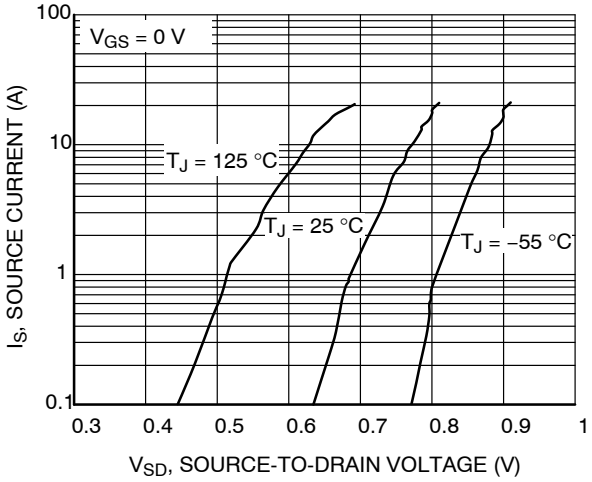



**Figure 10. Diode Forward Voltage vs. Current**

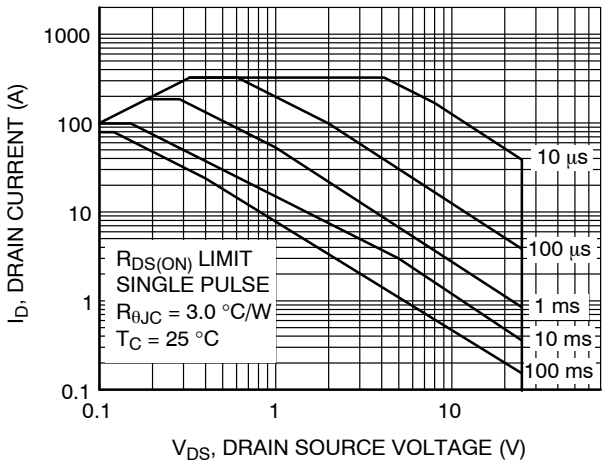



**Figure 11. Maximum Rated Forward Biased Safe Operationg Area**

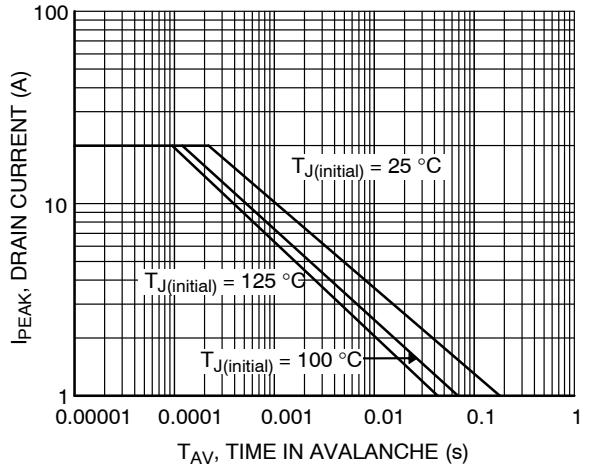



**Figure 12. Maximum Drain Current vs. Time in Avalanche**

## TYPICAL CHARACTERISTICS FOR Q1 (continued)

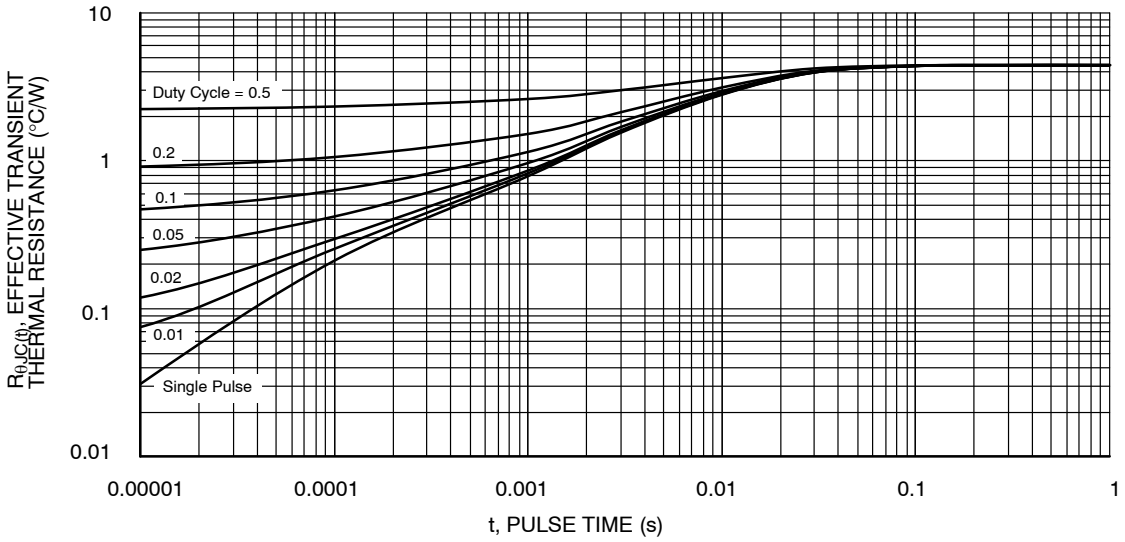



**Figure 13. Thermal Response**

## TYPICAL CHARACTERISTICS FOR Q2

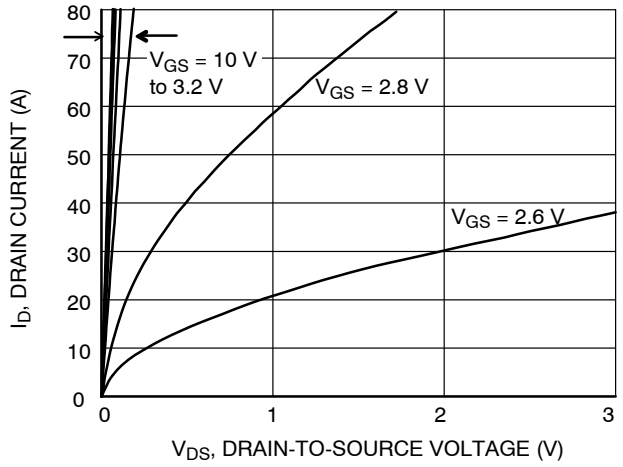



**Figure 14. On-Region Characteristics**

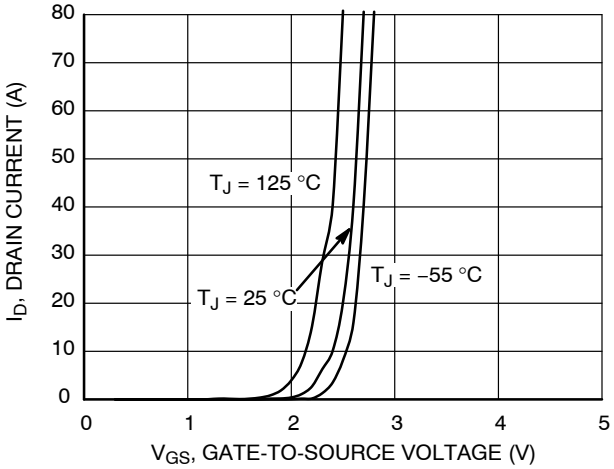



**Figure 15. Transfer Characteristics**

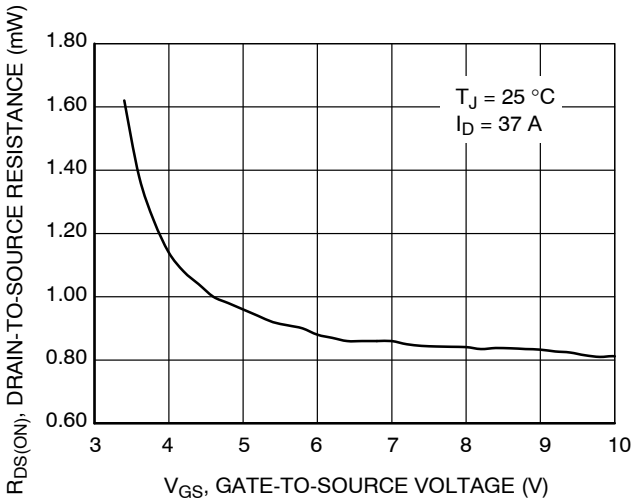



**Figure 16. On-Resistance vs. Gate-to-Source Voltage**

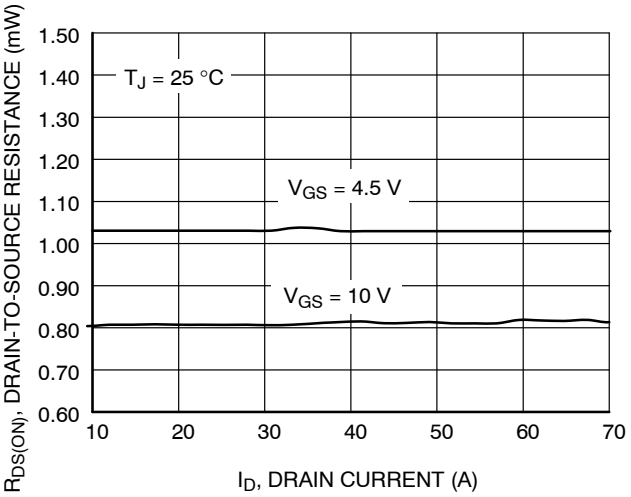



**Figure 17. On-Resistance vs. Drain Current and Gate Voltage**

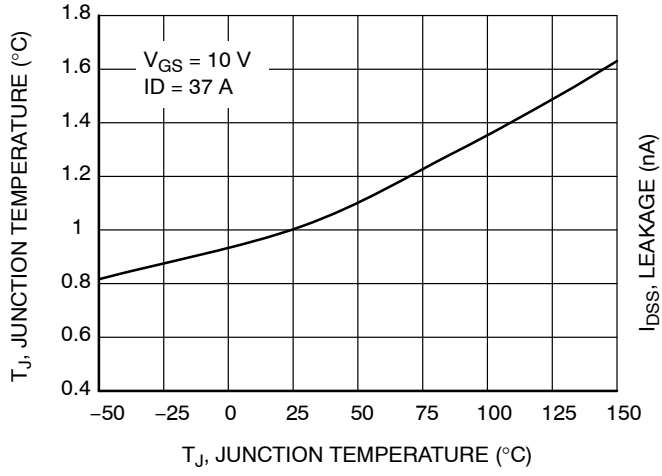



**Figure 18. On-Resistance Variation with Temperature**

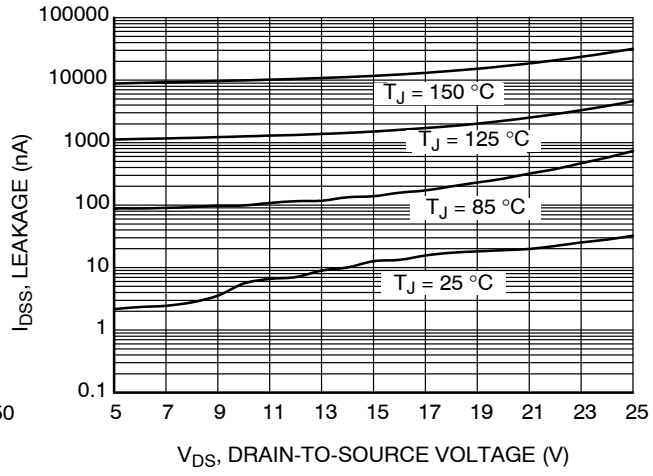



**Figure 19. Drain-to-Source Leakage Current vs. Voltage**

## TYPICAL CHARACTERISTICS FOR Q2 (continued)

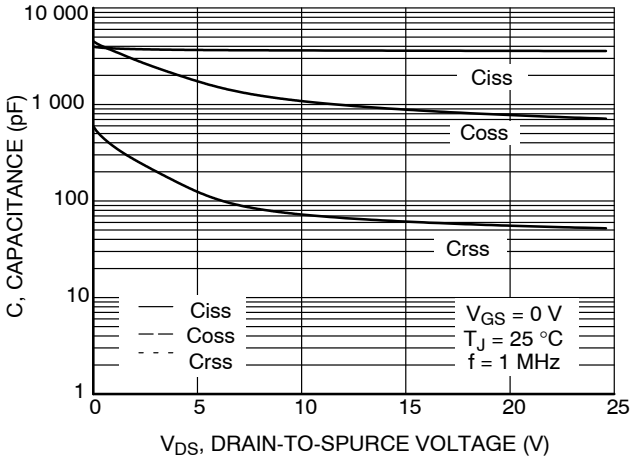



**Figure 20. Capacitance Variation**

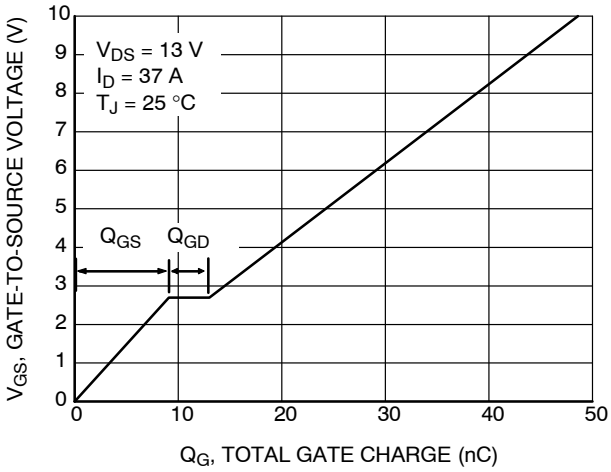



**Figure 21. Gate-to-Source vs. Total Charge**

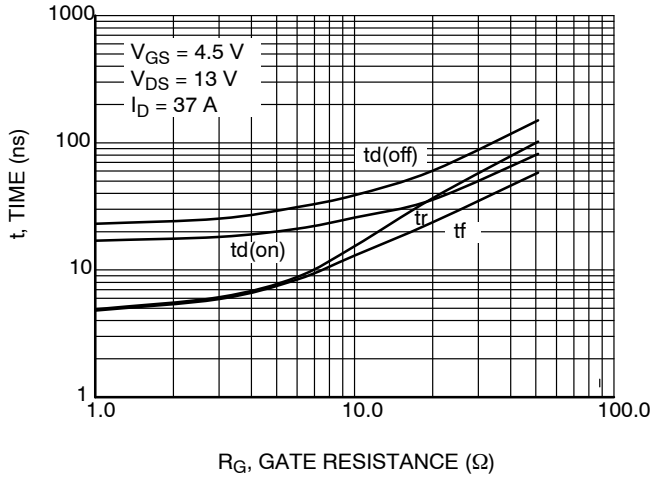



**Figure 22. Resistive Switching Time Variation vs. Gate Resistance**

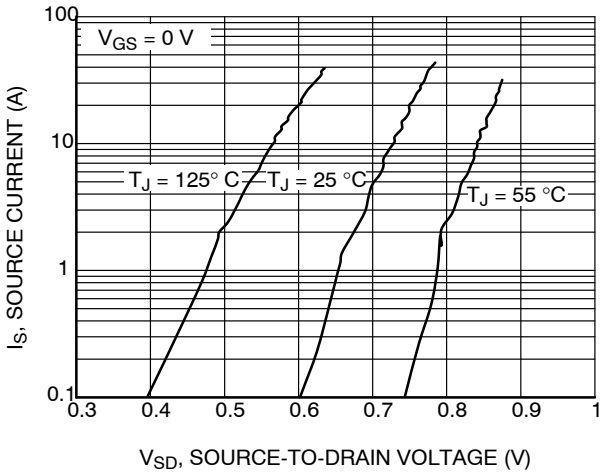



**Figure 23. Diode Forward Voltage vs. Current**

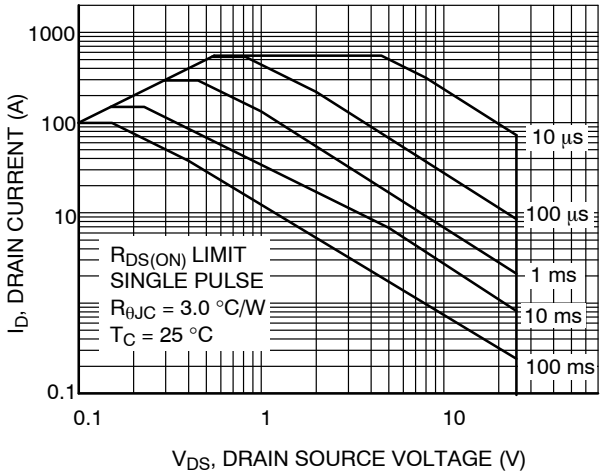



**Figure 24. Maximum Rated Forward Biased Safe Operating Area**

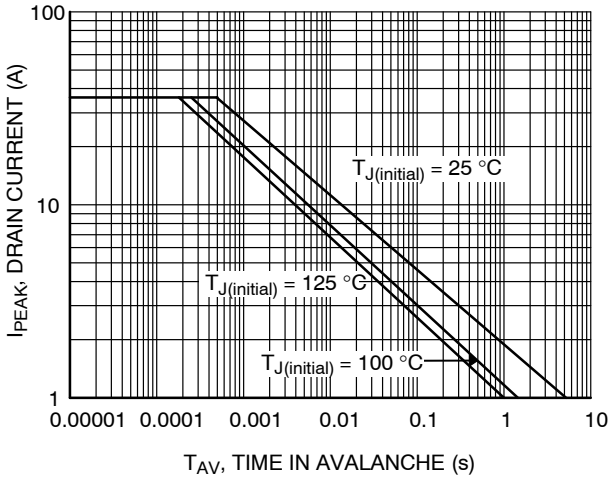



**Figure 25. Maximum Drain Current vs. Time in Avalanche**

## TYPICAL CHARACTERISTICS FOR Q2 (continued)

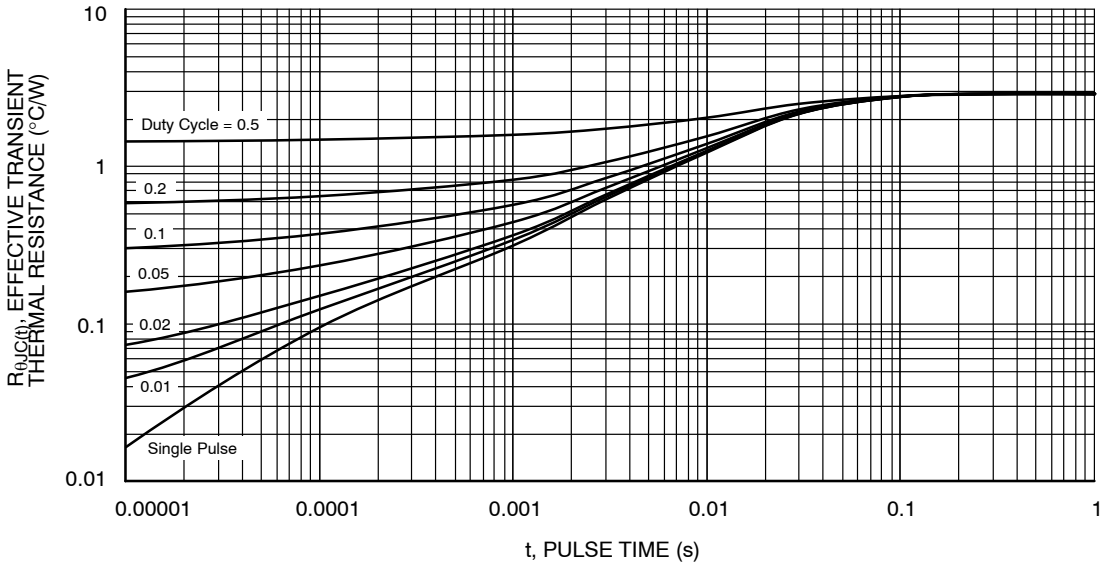
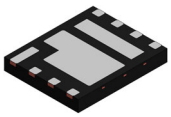



**Figure 26. Thermal Response**

## REVISION HISTORY

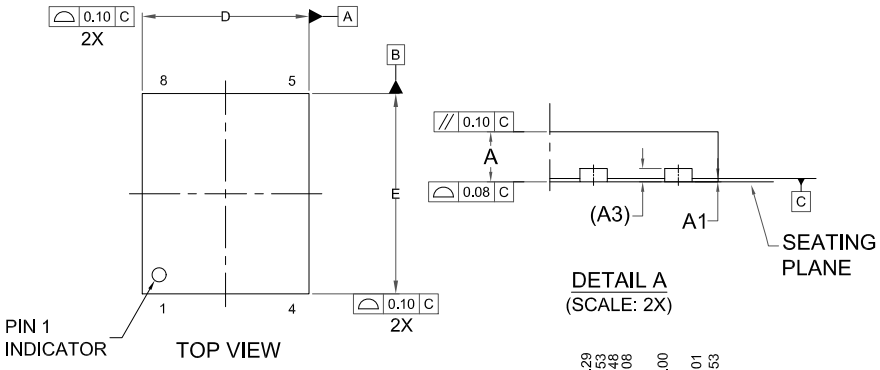
| Revision | Description of Changes | Date |
|---|---|---|
| 2 | Document rebranded to **onsemi** format. | 11/5/2025 |

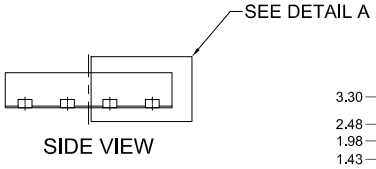
This document has undergone updates prior to the inclusion of this revision history table. The changes tracked here only reflect updates made on the noted approval dates.

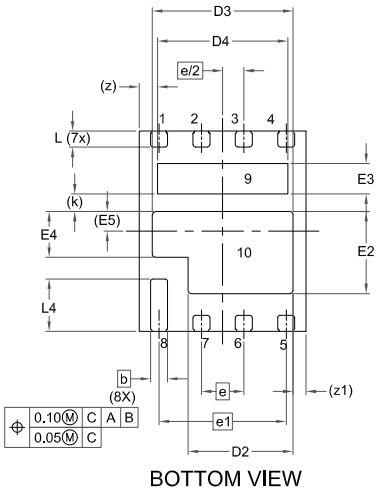


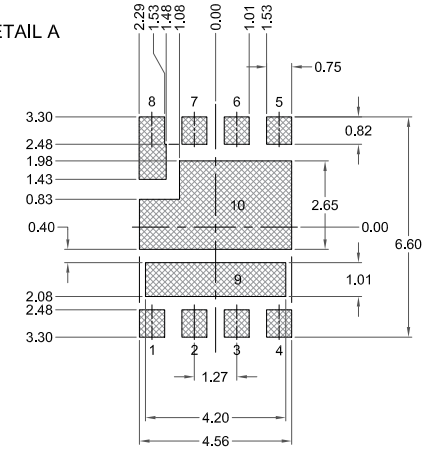
**PQFN8 5.00x6.00x0.75, 1.27P**
CASE 483AR
ISSUE D

DATE 06 NOV 2023




RECOMMENDED LAND PATTERN

*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

NOTES: UNLESS OTHERWISE SPECIFIED

A) DOES NOT FULLY CONFORM TO JEDEC REGISTRATION, MO-229, DATED 11/2001.
B) ALL DIMENSIONS ARE IN MILLIMETERS.
C) DIMENSIONS DO NOT INCLUDE BURRS OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM.
D) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

| DIM | MILLIMETERS | | |
|---|---|---|---|
| | MIN. | NOM. | MAX. |
| A | 0.70 | 0.75 | 0.80 |
| A1 | 0.00 | - | 0.05 |
| A3 | | 0.20 REF | |
| b | | 0.51 BSC | |
| D | 4.90 | 5.00 | 5.10 |
| D2 | 3.05 | 3.15 | 3.25 |
| D3 | 4.12 | 4.22 | 4.32 |
| D4 | 3.80 | 3.90 | 4.00 |
| E | 5.90 | 6.00 | 6.10 |
| E2 | 2.36 | 2.46 | 2.56 |
| E3 | 0.81 | 0.91 | 1.01 |
| E4 | 1.27 | 1.37 | 1.47 |
| E5 | | 0.59 REF | |
| e | | 1.27 BSC | |
| e/2 | | 0.635 BSC | |
| e1 | | 3.81 BSC | |
| k | | 0.52 REF | |
| L | 0.38 | 0.48 | 0.58 |
| L4 | 1.47 | 1.57 | 1.67 |
| z | | 0.55 REF | |
| z1 | | 0.39 REF | |

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| **DESCRIPTION:** | **PQFN8 5.00x6.00x0.75, 1.27P** | | **PAGE 1 OF 1** |

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